SCLS409B - APRIL 1998 - REVISED NOVEMBER 1998

- **EPIC** ™ (Enhanced-Performance Implanted **CMOS) Process**
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at V_{CC} = 3.3 V, T_A = 25°C
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- **ESD Protection Exceeds 2000 V Per** MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- **Package Options Include Plastic** Small-Outline (DW, NS), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Packages, Chip Carriers (FK), and DIPs (J)

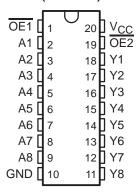
description

The 'LV540A devices are octal buffers/drivers designed for 2-V to 5.5-V V_{CC} operation.

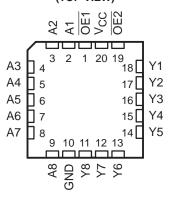
These devices are ideal for driving bus lines or buffer memory address registers. They feature inputs and outputs on opposite sides of the package to facilitate printed circuit board layout.

The 3-state control gate is a two-input AND gate with active-low inputs so that if either output-enable ($\overline{OE1}$ or $\overline{OE2}$) input is high, all corresponding outputs are in the high-impedance state. The outputs provide inverted data when they are not in the high-impedance state.

SN54LV540A . . . J OR W PACKAGE SN74LV540A . . . DB, DGV, DW, NS, OR PW PACKAGE (TOP VIEW)



SN54LV540A . . . FK PACKAGE (TOP VIEW)



To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54LV540A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74LV540A is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each buffer/driver)

	INPUTS	OUTPUT				
OE1	OE2	Α	Y			
L	L	L	Н			
L	L	Н	L			
Н	X	Χ	Z			
Х	Н	Χ	Z			

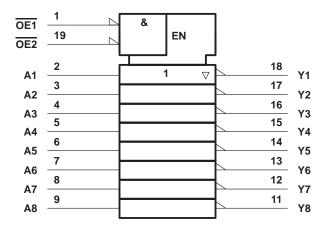


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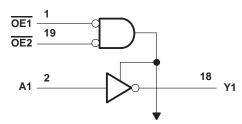


logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. This value is limited to 7 V maximum.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 4)

			SN54L	SN54LV540A		.V540A	LINUT
			MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage		2	5.5	2	5.5	V
V.		V _{CC} = 2 V	1.5		1.5		
	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V _{CC} ×0.7		$V_{CC} \times 0.7$		V
VIH	riigii-ievei iriput voitage	$V_{CC} = 3 V \text{ to } 3.6 V$	V _{CC} ×0.7		$V_{CC} \times 0.7$		V
		V _{CC} = 4.5 V to 5.5 V	V _{CC} ×0.7		$V_{CC} \times 0.7$		
		V _{CC} = 2 V		0.5		0.5	
V	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		V _{CC} × 0.3		V _{CC} ×0.3	V
VIL	Low-level input voltage	$V_{CC} = 3 V \text{ to } 3.6 V$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	v
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		V _{CC} ×0.3		V _{CC} ×0.3	
٧ _I	Input voltage		0	5.5	0	5.5	V
\/o	Output voltage	High or low state	0	⁴ √V _{CC}	0	V _{CC}	V
VO	Output voltage	3-state	0	5.5	0	5.5	V
		V _{CC} = 2 V	2	-50		-50	μΑ
lou	High-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	30	-2		-2	
ЮН	riigii-ievei output current	$V_{CC} = 3 V \text{ to } 3.6 V$	0	-8		-8	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-16		-16	
		V _{CC} = 2 V		50		50	μΑ
lai	Low-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2		2	
lOL	Low-level output current	$V_{CC} = 3 V \text{ to } 3.6 V$		8		8	mA
		V _{CC} = 4.5 V to 5.5 V		16		16	
		V _{CC} = 2.3 V to 2.7 V	0	200	0	200	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3 V \text{ to } 3.6 V$	0	100	0	100	ns/V
		V _{CC} = 4.5 V to 5.5 V	0	20	0	20	
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	,,	SN54LV540A	SN74LV540A	UNIT
PARAWETER	TEST CONDITIONS	VCC	MIN TYP MAX	MIN TYP MAX	UNIT
	$I_{OH} = -50 \mu A$	2 V to 5.5 V	V _{CC} -0.1	V _{CC} -0.1	
Vall	I _{OH} = -2 mA	2.3 V	2	2	V
VOH	I _{OH} = -8 mA	3 V	2.48	2.48	v
	I _{OH} = -16 mA	4.5 V	3.8	3.8	
	I _{OL} = 50 μA	2 V to 5.5 V	Ø 0.1	0.1	
Val	I _{OL} = 2 mA	2.3 V	0.4	0.4	V
VOL	I _{OL} = 8 mA	3 V	0.44	0.44	v
	I _{OL} = 16 mA	4.5 V	0.55	0.55	
lį	$V_I = V_{CC}$ or GND	5.5 V	9 ±1	±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V	±5	±5	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	20	μΑ
l _{off}	V_I or $V_O = 0$ to 5.5 V	0 V	5	5	μΑ
C.	Vi – Vo a ar CND	3.3 V	2.5	2.5	»E
Ci	V _I = V _{CC} or GND	5 V	2.5	2.5	pF

switching characteristics over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO		LOAD	T _A = 25°C		SN54LV540A		SN74LV540A		UNIT	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t pd*	А	Υ			5.6	12	1	14.5	1	14.5	
ten*	ŌE	Υ	C _L = 15 pF		7.8	17.4	1	21	1	21	ns
^t dis*	ŌE	Υ	1 [5.7	16	1	19	1	19	
^t pd	А	Υ			7.9	16.8	1/	18.5	1	18.5	
t _{en}	ŌE	Υ	0 50 5		10.1	22.2	77/	25.5	1	25.5	
^t dis	ŌE	Υ	C _L = 50 pF		8.1	22.3	Q ² 1	25.5	1	25.5	ns
t _{sk(o)} †						2	Q			2	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	λ = 25°C	;	SN54L	V540A	SN74L	V540A	UNIT
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
tpd*	А	Υ			4.1	7	1	8.5	1	8.5	
t _{en} *	ŌE	Υ	C _L = 15 pF		5.6	10.5	1	12.5	1	12.5	ns
^t dis [*]	ŌE	Υ	1		4.2	10.5	1	12.5	1	12.5	
^t pd	А	Υ			5.8	10.5	1/	12	1	12	
t _{en}	ŌE	Υ	0 50 - 5		7.3	14	277/	16	1	16	
^t dis	ŌE	Υ	$C_L = 50 pF$		5.8	15.4	0 1	17.5	1	17.5	ns
t _{sk(o)} †						1.5	Q			1.5	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

[†] Skew between any two outputs of the same package switching in the same direction



[†] Skew between any two outputs of the same package switching in the same direction

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO		LOAD	T _A = 25°C		SN54LV540A		SN74LV540A		UNIT	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
tpd*	А	Υ			3	5	1	6	1	6	
t _{en} *	ŌĒ	Υ	C _L = 15 pF		4.1	7.2	1	8.5	1	8.5	ns
^t dis*	ŌE	Υ	1 1		2.9	7	1	8	1	8	
^t pd	А	Υ			4.2	7	1/	. 8	1	8	
t _{en}	ŌE	Υ	0 50 5		5.3	9.2	277/	10.5	1	10.5	
^t dis	ŌĒ	Υ	C _L = 50 pF		3.5	8.8	O 1	10	1	10	ns
t _{sk(o)} †						1	Q.			1	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, V_{CC} = 3.3 V, C_L = 50 pF, T_A = 25°C (see Note 5)

	PARAMETER		SN74LV540A			
	PARAMETER				UNIT	
V _{OL(P)}	Quiet output, maximum dynamic VOL		0.54	0.8	V	
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.28	-0.8	V	
VOH(V)	Quiet output, minimum dynamic VOH		3.03		V	
VIH(D)	High-level dynamic input voltage	2.3			V	
V _{IL(D)}	Low-level dynamic input voltage			0.97	V	

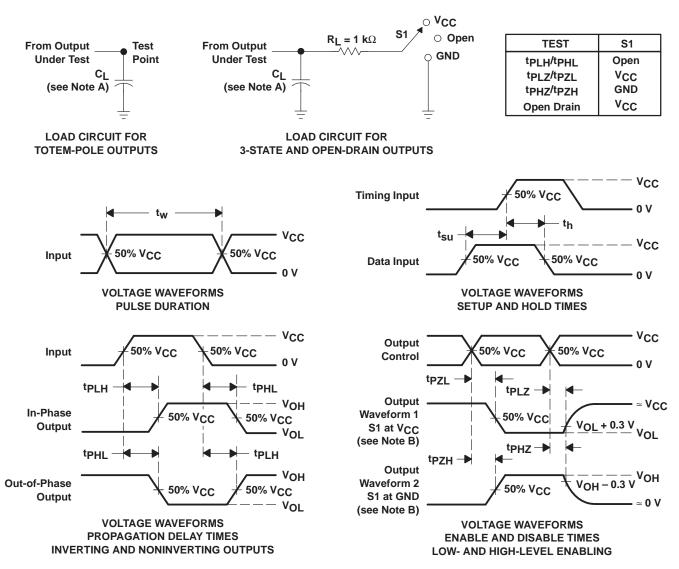
NOTE 5: Characteristics are for surface-mount packages only.

operating characteristics, T_A = 25°C

PARAMETER			TEST CO	VCC	TYP	UNIT	
C _{pd}	Dawar dissination conscitones	Outputs enabled	C. 50 pF	f 40 MH-	3.3 V	10	pF
	Power dissipation capacitance	Outputs enabled	$C_L = 50 pF$,	f = 10 MHz	5 V	11	

 $[\]ensuremath{^{\dagger}}$ Skew between any two outputs of the same package switching in the same direction

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_I includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tpl 7 and tpH7 are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tpHL and tpLH are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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